

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/631,004	HACKL, THOMAS	
Examiner		Art Unit	Devon C Kramer	
		3683	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0036352 A1	02-2004	Neuhaus et al.	303/191
	B	US-6,044,321 A	03-2000	Nakamura et al.	701/96
	C	US-6,226,593 B1	05-2001	Kurz et al.	701/301
	D	US-6,253,144 B1	06-2001	Yamamura et al.	701/96
	E	US-6,311,122 B1	10-2001	Higashimata, Akira	701/96
	F	US-6,470,257 B1	10-2002	Seto, Yoji	701/96
	G	US-6,687,595 B2	02-2004	Seto et al.	701/96
	H	US-5,864,285 A	01-1999	Wieder et al.	340/435
	I	US-2002/0152015 A1	10-2002	Seto, Yoji	701/96
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.